- Fully Synchronous Operation for Counting and Programming
- Internal Carry Look-Ahead Circuitry for Fast Counting
- Carry Output for n-Bit Cascading
- Fully Independent Clock Circuit
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

### description

These synchronous 4-bit up/down binary presettable counters feature an internal carry look-ahead circuitry for cascading in high-speed counting applications. Synchronous operation is provided by having all flip-flops clocked simultaneously so that the outputs change coincident with each other when so instructed by the count-enable (ENP, ENT) inputs and internal gating. This mode of operation eliminates the output counting spikes normally associated with asynchronous (ripple-clock) counters. A buffered clock (CLK) input triggers the four flip-flops on the rising (positive-going) edge of the clock waveform.

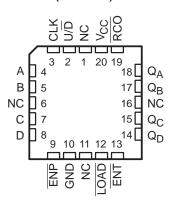
These counters are fully programmable; that is, they may be preset to either level. The load-input circuitry allows loading with the carry-enable output of cascaded counters. Because loading is synchronous, setting up a low level at the load (LOAD) input disables the counter and causes the outputs to agree with the data inputs after the next clock pulse.

SN54ALS169B, SN54AS169A ... J PACKAGE SN74ALS169B, SN74AS169A ... D OR N PACKAGE (TOP VIEW)

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	(		,	
U/D CLK A C C C C D ENP GND	2 3 4 5 6 7	Ο	16 15 14 13 12 11 10 9	V <sub>CC</sub> RCO Q <sub>A</sub> Q <sub>B</sub> Q <sub>C</sub> Q <sub>D</sub> ENT LOAD

#### SN54ALS169B, SN54AS169A...FK PACKAGE (TOP VIEW)



NC - No internal connection

The internal carry look-ahead circuitry provides for cascading counters for n-bit synchronous application without additional gating.  $\overline{ENP}$  and  $\overline{ENT}$  inputs and a ripple-carry output ( $\overline{RCO}$ ) are instrumental in accomplishing this function. Both  $\overline{ENP}$  and  $\overline{ENT}$  must be low to count. The direction of the count is determined by the level of the up/down ( $U/\overline{D}$ ) input. When  $U/\overline{D}$  is high, the counter counts up; when low, it counts down.  $\overline{ENT}$  is fed forward to enable  $\overline{RCO}$ .  $\overline{RCO}$ , thus enabled, produces a low-level pulse while the count is zero (all inputs low) counting down or maximum (15) counting up. This low-level overflow ripple-carry pulse can be used to enable successive cascaded stages. Transitions at  $\overline{ENP}$  or  $\overline{ENT}$  are allowed regardless of the level of the clock input. All inputs are diode clamped to minimize transmission-line effects, thereby simplifying system design.

These counters feature a fully independent clock circuit. Changes at control inputs ( $\overline{ENP}$ ,  $\overline{ENT}$ ,  $\overline{LOAD}$ , or  $U/\overline{D}$ ) that modify the operating mode have no effect on the contents of the counter until clocking occurs. The function of the counter (whether enabled, disabled, loading, or counting) is dictated solely by the conditions meeting the stable setup and hold times.

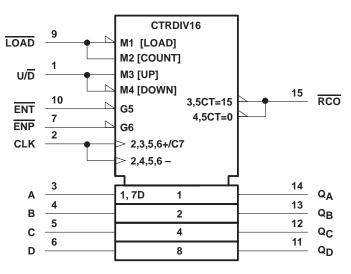
The SN54ALS169B and SN54AS169A are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS169B and SN74AS169A are characterized for operation from 0°C to 70°C.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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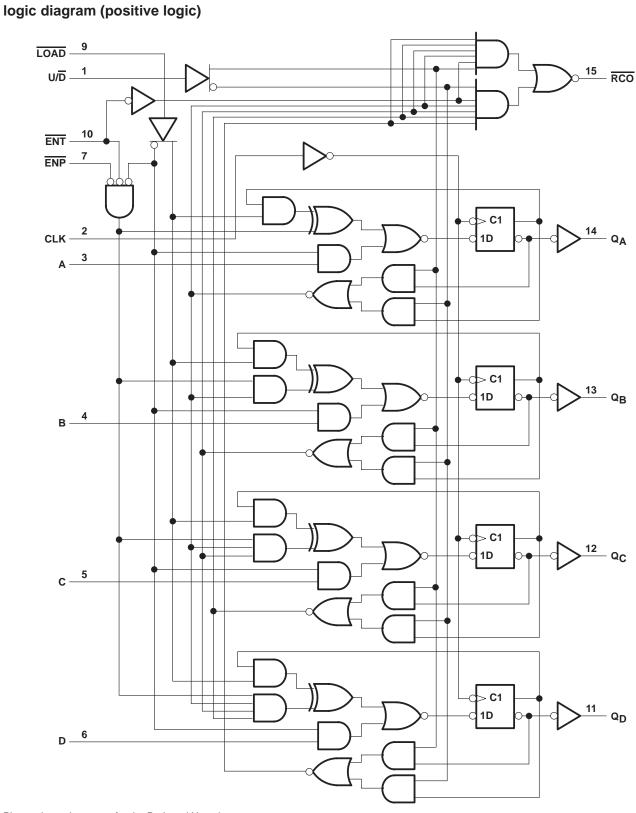
### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.



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Pin numbers shown are for the D, J, and N packages.

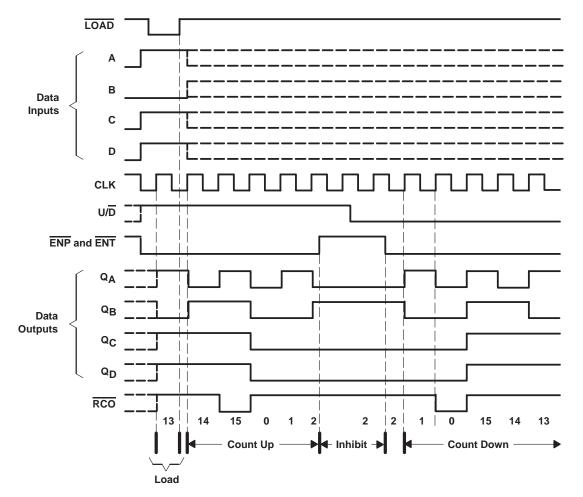


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### typical load, count, and inhibit sequences

The following sequence is illustrated below:

- 1. Load (preset) to binary 13
- 2. Count up to 14, 15 (maximum), 0, 1, and 2
- 3. Inhibit
- 4. Count down to 1, 0 (minimum), 15, 14, and 13



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>CC</sub> Input voltage, V <sub>I</sub>	
Operating free-air temperature range, T <sub>A</sub> : SN54ALS169B	–55°C to 125°C
	0°C to 70°C
Storage temperature range	−65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



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recommended	operating	conditions	

			SNS	54ALS16	69B	SN74ALS169B		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V
ЮН	High-level output current				-0.4			-0.4	mA
IOL	Low-level output current				4			8	mA
fclock	Clock frequency		0		22	0		40	MHz
tw	Pulse duration, CLK high or low		14			12.5			ns
		A, B, C, or D	20			15			
	Setur time before CLK <sup>↑</sup>	ENP or ENT	25			15			
t <sub>su</sub>	Setup time before CLK↑	LOAD	20			15			ns
		U/D	28			15			
t <sub>h</sub>	Hold time, data after $CLK^\uparrow$		0			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			SN	SN54ALS169B			SN74ALS169B		
PARAMETER	TEST C	TEST CONDITIONS		түр†	MAX	MIN	TYP†	MAX	UNIT
VIK	V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = –18 mA			-1.5			-1.5	V
VOH	V <sub>CC</sub> = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> –2	2		V <sub>CC</sub> -2	2		V
Vol	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 4 mA		0.25	0.4		0.25	0.4	V
VOL		I <sub>OL</sub> = 8 mA					0.35	0.5	v
Ц	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA
ЧН	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
١ <sub>١L</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.2			-0.2	mA
10 <sup>‡</sup>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-20		-112	-30		-112	mA
ICC	V <sub>CC</sub> = 5.5 V			15	25		15	25	mA

<sup>†</sup> All typical values are at  $V_{CC}$  = 5 V,  $T_A$  = 25°C.

<sup>‡</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



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### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)		$V_{CC}$ = 4.5 V to 5.5 V, $C_{L}$ = 50 pF, $R_{L}$ = 500 $\Omega$ , $T_{A}$ = MIN to MAX <sup>†</sup>				
			SN54AL	S169B	SN74AL	S169B		
			MIN	MAX	MIN	MAX		
fmax			22		40		MHz	
<sup>t</sup> PLH	CLK		3	20	3	20	20	
<sup>t</sup> PHL		RCO	6	25	6	20	ns	
<sup>t</sup> PLH	CLK	Any Q	2	20	2	15	ns	
<sup>t</sup> PHL	ULK	Ally Q	5	23	5	20	115	
<sup>t</sup> PLH		<b>B00</b>	2	16	2	13	ns	
<sup>t</sup> PHL	ENT	RCO	3	24	3	16	115	
<sup>t</sup> PLH	U/D	RCO	4	22	5	19	ns	
<sup>t</sup> PHL	0/0	KCU	5	26	5	19	115	

<sup>+</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>‡</sup>

Supply voltage, V <sub>CC</sub>	
Input voltage, V <sub>I</sub>	
Operating free-air temperature range, TA: SN54AS169A	
SN74AS169A .	
Storage temperature range	–65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

			SN	54AS16	9A	SN74AS169A		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.8			0.8	V
ЮН	High-level output current				-2			-2	mA
IOL	Low-level output current				20			20	mA
fclock*	Clock frequency		0		60	0		75	MHz
tw*	Pulse duration, CLK high or low		7.7			6.7			ns
		A, B, C, or D	10			8			
+ *	Setup time before CLK↑	ENP or ENT	10			8			ns
t <sub>su</sub> *	Setup time before CER I	LOAD	10			8			115
		U/D	14			11			
t <sub>h</sub> *	Hold time, data after $CLK^\uparrow$		2			0			ns
Т <sub>А</sub>	Operating free-air temperature		-55		125	0		70	°C

\* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.



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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	SN54AS169A			SN74AS169A			
		TESTCON	DITIONS	MIN	TYP†	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT	
VIK		V <sub>CC</sub> = 4.5 V,	l <sub>l</sub> = -18 mA			-1.2			-1.2	V	
VOH		V <sub>CC</sub> = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V <sub>CC</sub> -2	2		V <sub>CC</sub> -2	2		V	
VOL		$V_{CC} = 4.5 V,$	I <sub>OL</sub> = 20 mA		0.25	0.5		0.25	0.5	V	
łı	LOAD, ENT, U/D		V <sub>1</sub> = 7 V			0.2			0.2	mA	
	All others	V <sub>CC</sub> = 5.5 V,				0.1			0.1		
I	LOAD, ENT, U/D		V <sub>I</sub> = 2.7 V			40			40	μA	
ін	All others	$V_{CC} = 5.5 V,$				20			20	μΑ	
1	LOAD, ENT, U/D		$\lambda = 0.4 \lambda$			-1			-1	mA	
ΊL	All others	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 0.4 V			-0.5			-0.5	ША	
10‡		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	-30		-112	mA	
ICC		V <sub>CC</sub> = 5.5 V			41	63		41	63	mA	

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

<sup>‡</sup>The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

### switching characteristics (see Figure 1)

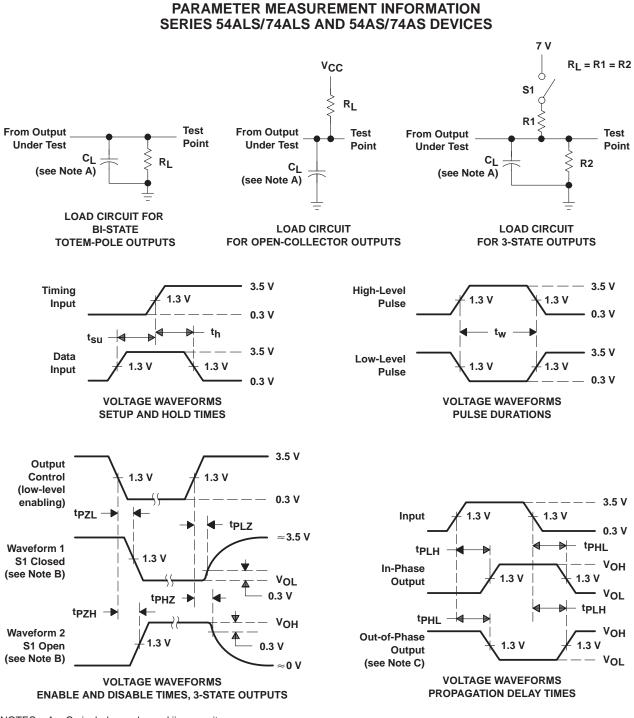
PARAMETER	FROM (INPUT)	ТО (OUTPUT)	VC CL RL TA	UNIT			
			SN54A	S169A	SN74A	S169A	
			MIN	MAX	MIN	MAX	
f <sub>max</sub> *			60		75		MHz
<sup>t</sup> PLH	CLK	RCO	3	17.5	3	16.5	
<sup>t</sup> PHL		(LOAD high or low)	2	14	2	13	ns
<sup>t</sup> PLH	CLK	Amy O	1	7.5	1	7	
<sup>t</sup> PHL	ULK	Any Q	2	14	2	13	ns
<sup>t</sup> PLH			1.5	10	1.5	9	ns
<sup>t</sup> PHL	ENT	RCO	1.5	10	1.5	9	115
<sup>t</sup> PLH	U/D	RCO	2	14	2	12	200
<sup>t</sup> PHL	0/D	RCO	2	14.5	2	13	ns

\* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

\$ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz, t<sub>f</sub> = t<sub>f</sub> = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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